N-channel 600 V, 370 mΩ typ., 10 A FDmesh II Power MOSFET in an I²PAK package

TAB

I²PAK

D(2, TAB)

G(1)

S(3)

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STPOWER
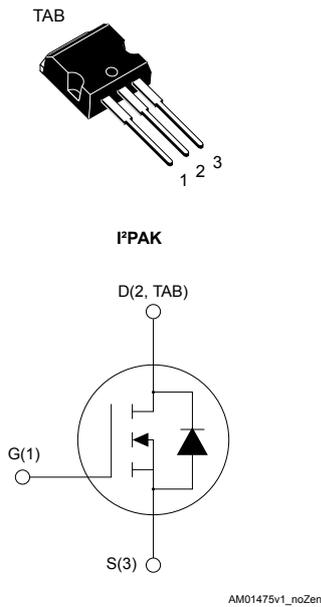
Features

Order code	V_{DS} at T_J max.	$R_{DS(on)}$ max.	I_D
STI11NM60ND	650 V	450 mΩ	10 A

- Fast-recovery body diode
- Low gate charge and input capacitance
- Low on-resistance $R_{DS(on)}$
- 100% avalanche tested
- High dv/dt ruggedness

Applications

- Switching applications

Description

This FDmesh II Power MOSFET with fast-recovery body diode is produced using MDmesh II technology. Utilizing a new strip-layout vertical structure, this device features low on-resistance and superior switching performance. It is ideal for bridge topologies and ZVS phase-shift converters.

Product status link

STI11NM60ND

Product summary

Product summary	
Order code	STI11NM60ND
Marking	11NM60ND
Package	I²PAK
Packing	Tube

DS14349 - Rev 1 - June 2023
For further information contact your local STMicroelectronics sales office.

www.st.com

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	600	V
V_{GS}	Gate-source voltage	±25	V
I_D	Drain current (continuous) at T_C = 25 °C	10	A
	Drain current (continuous) at T_C = 100 °C	6.3	
I_{DM}[1]	Drain current (pulsed)	40	A
P_{TOT}	Total power dissipation at T_C = 25 °C	90	W
dv/dt[2]	Peak diode recovery voltage slope	40	V/ns
T_{stg}	Storage temperature range	-55 to 150	°C
T_J	Maximum operating junction temperature	150	°C

1. *Pulse width is limited by safe operating area.*
2. *$I_{SD} \leq 10$ A, di/dt $\leq$ 400 A/µs, V_{DS} (peak) < $V_{(BR)DSS}$, V_{DD} = 80% $V_{(BR)DSS}$.*

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance, junction-to-case	1.38	°C/W
R_{thJA}	Thermal resistance, junction-to-ambient	62.5	°C/W

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AS}	Avalanche current, repetitive or non-repetitive (pulse width limited by T_J max.)	3.5	A
E_{AS}	Single pulse avalanche energy (starting T_J = 25 °C, I_D = I_{AS}, V_{DD} = 50 V)	200	mJ

2 Electrical characteristics

T_C = 25 °C unless otherwise specified.

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS} = 0 V, I_D = 1 mA	600			V
dv/dt[1]	Drain-source voltage slope	V_{DD} = 480 V, I_D = 10 A, V_{GS} = 10 V		45		V/ns
I_{DSS}	Zero gate voltage drain current	V_{GS} = 0 V, V_{DS} = 600 V			1	µA
		V_{GS} = 0 V, V_{DS} = 600 V, T_C = 125 °C[2]			100	
I_{GSS}	Gate-body leakage current	V_{DS} = 0 V, V_{GS} = ±20 V			±100	nA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 250 µA	3	4	5	V
$R_{DS(on)}$	Static drain-source on-resistance	V_{GS} = 10 V, I_D = 5 A		370	450	mΩ

1. Value measured at turn off under inductive load.
2. Specified by design, not tested in production.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} = 50 V, f = 1 MHz, V_{GS} = 0 V	-	850	-	pF
C_{oss}	Output capacitance		-	44	-	pF
C_{rss}	Reverse transfer capacitance		-	5	-	pF
$C_{oss\ eq.}$ [1]	Equivalent output capacitance	V_{GS} = 0 V, V_{DS} = 0 to 480 V	-	130	-	pF
R_G	Gate input resistance	f = 1 MHz, I_D = 0 A	-	3.7	-	Ω
Q_g	Total gate charge	V_{DD} = 480 V, I_D = 10 A, V_{GS} = 0 to 10 V	-	30	-	nC
Q_{gs}	Gate-source charge	(see Figure 13. Test circuit for gate charge behavior)	-	4	-	nC
Q_{gd}	Gate-drain charge		-	16	-	nC

1. $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	V_{DD} = 300 V, I_D = 10 A,	-	16	-	ns
t_r	Rise time	R_G = 4.7 Ω, V_{GS} = 10 V	-	7	-	ns
$t_{d(off)}$	Turn-off delay time	(see Figure 12. Test circuit for resistive load switching times and	-	50	-	ns
t_f	Fall time	Figure 17. Switching time waveform)	-	9	-	ns

Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		10	A
I_{SDM}[1]	Source-drain current (pulsed)		-		40	A
V_{SD}[2]	Forward on voltage	I_{SD} = 10 A, V_{GS} = 0 V	-		1.3	V
t_{rr}	Reverse recovery time	I_{SD} = 10 A, di/dt = 100 A/µs,	-	130		ns
Q_{rr}	Reverse recovery charge	V_{DD} = 100 V	-	0.69		µC
I_{RRM}	Reverse recovery current	(see Figure 14. Test circuit for inductive load switching and diode recovery times)	-	11		A
t_{rr}	Reverse recovery time	I_{SD} = 10 A, di/dt = 100 A/µs,	-	200		ns
Q_{rr}	Reverse recovery charge	V_{DD} = 100 V, T_J = 150 °C	-	1.2		µC
I_{RRM}	Reverse recovery current	(see Figure 14. Test circuit for inductive load switching and diode recovery times)	-	12		A

1. *Pulse width is limited by safe operating area.*

2. *Pulsed: pulse duration = 300 µs, duty cycle 1.5%.*

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area
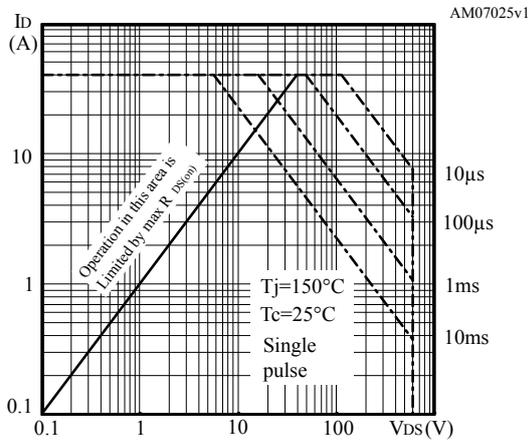
Figure 2. Normalized transient thermal impedance

$$Z_{th} = k * R_{thJC}$$
$$\delta = t_p / T$$
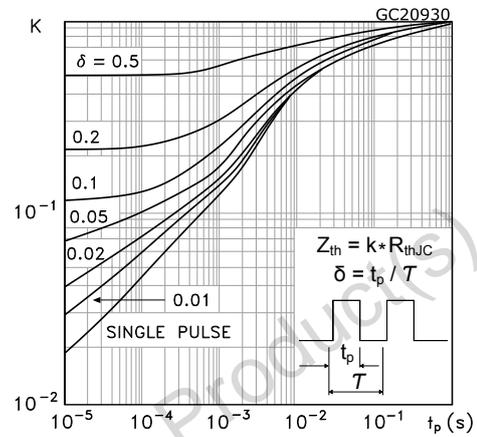
Figure 3. Typical drain-source on-resistance
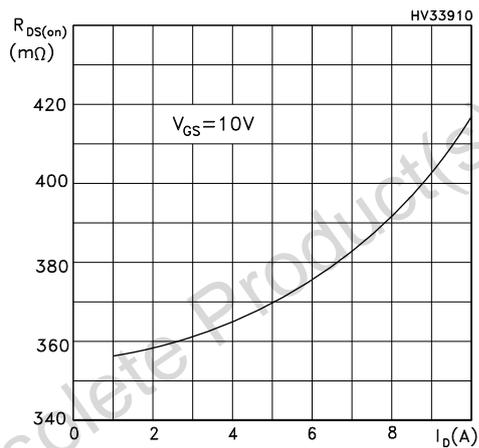
Figure 4. Typical output characteristics
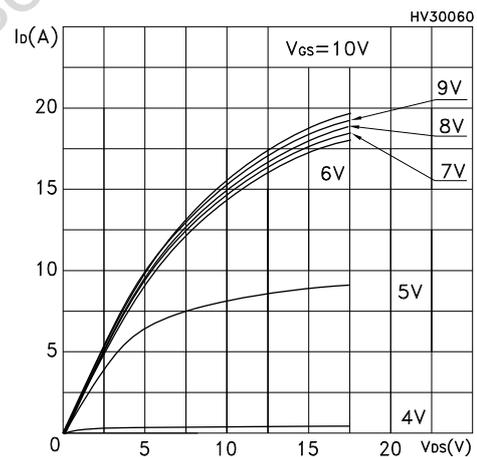

Figure 5. Typical transfer characteristics
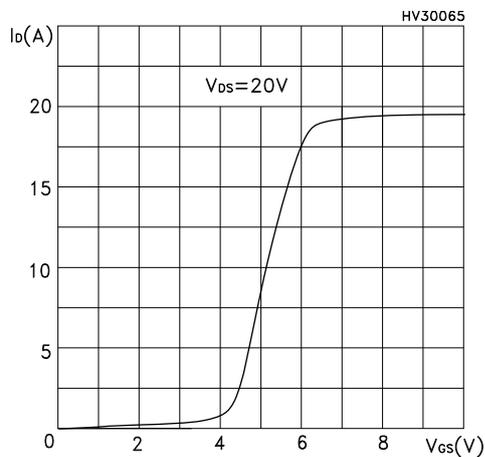

Figure 6. Normalized gate threshold vs temperature
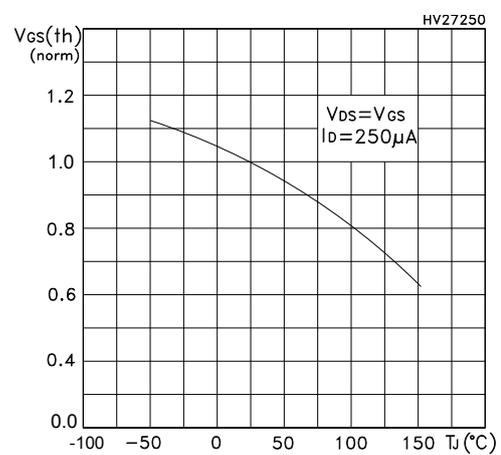
**Figure 7. Normalized breakdown voltage vs temperature**
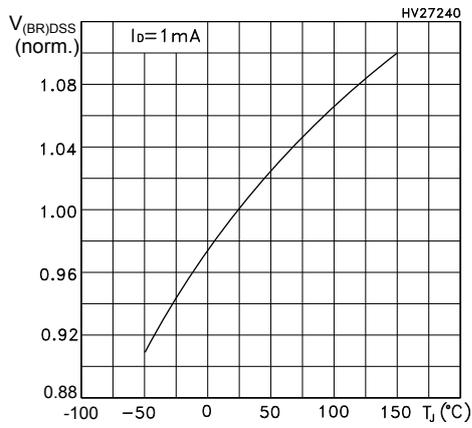

Figure 8. Normalized on-resistance vs temperature
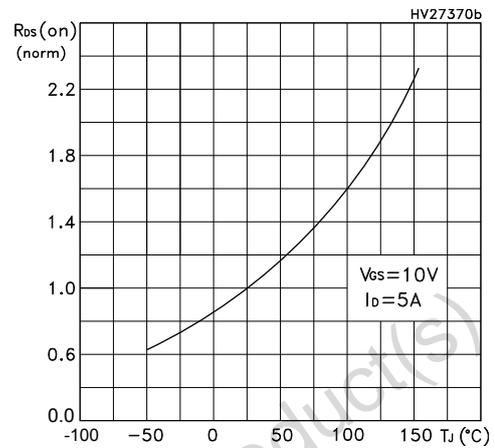
Figure 9. Typical gate charge characteristics
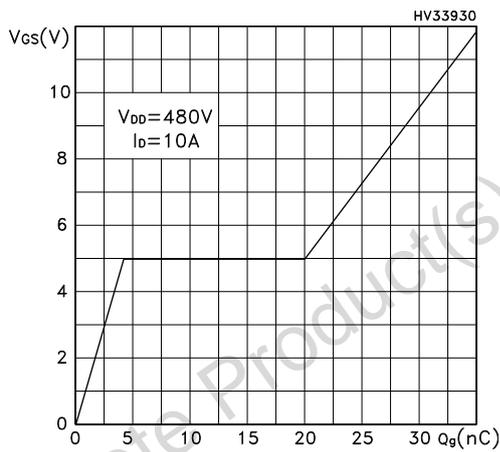

Figure 10. Typical capacitance characteristics
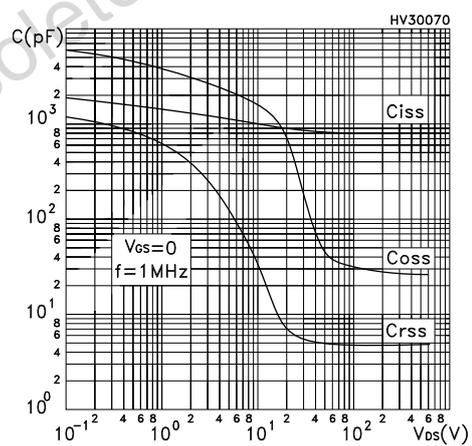

Figure 11. Typical reverse diode forward characteristics
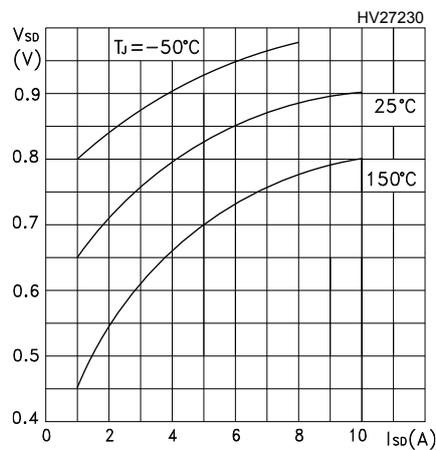
3 Test circuits

Figure 12. Test circuit for resistive load switching times
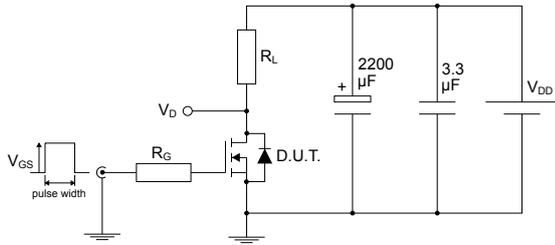

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**Figure 13. Test circuit for gate charge behavior**
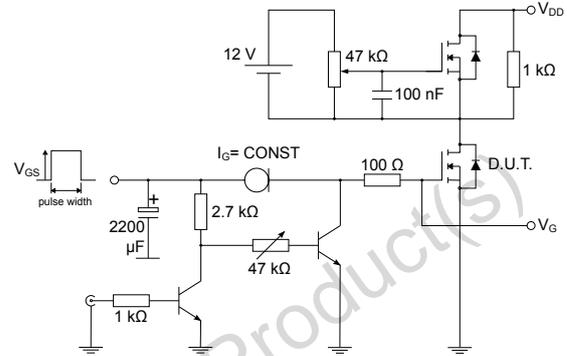
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**Figure 14. Test circuit for inductive load switching and diode recovery times**
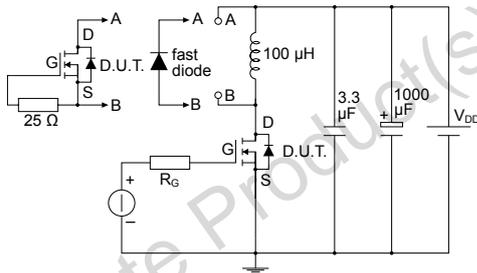
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Figure 15. Unclamped inductive load test circuit
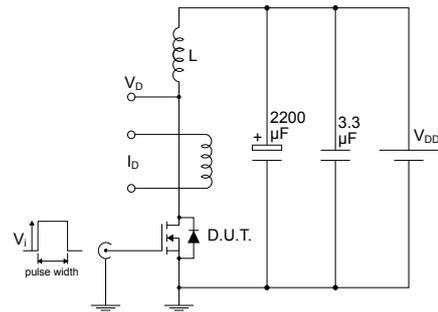
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Figure 16. Unclamped inductive waveform
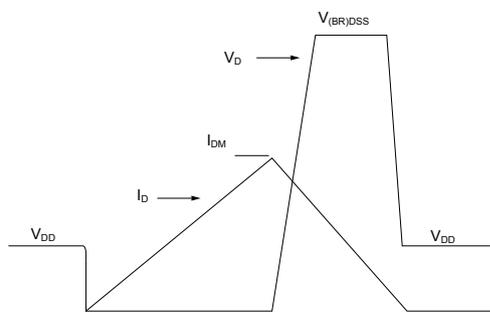

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Figure 17. Switching time waveform
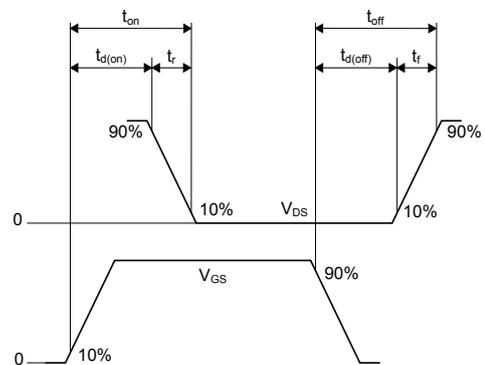
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4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 I²PAK package information

Figure 18. I²PAK package outline
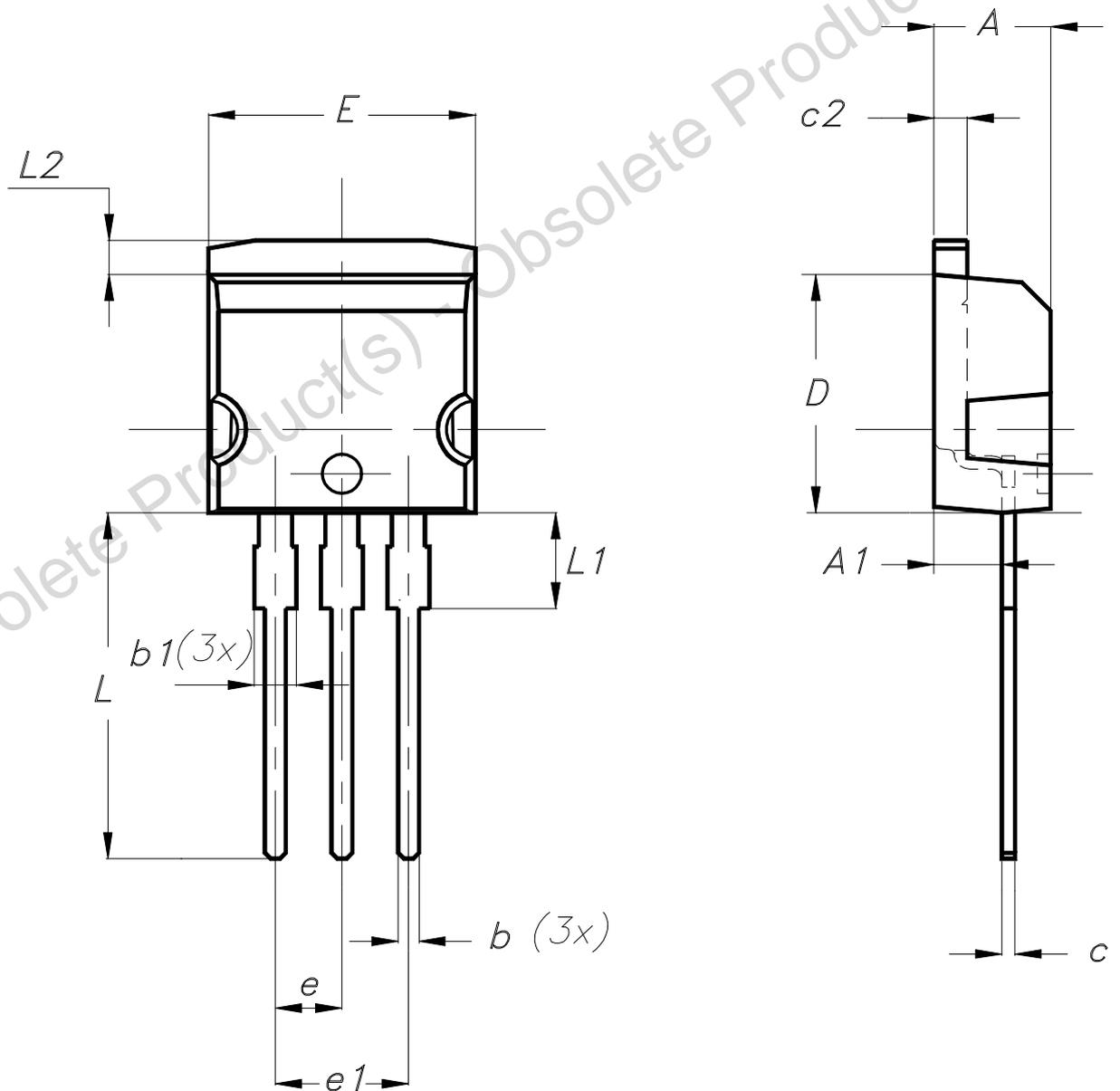
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Table 8. I²PAK package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40	-	4.60
A1	2.40	-	2.72
b	0.61	-	0.88
b1	1.14	-	1.70
c	0.49	-	0.70
c2	1.23	-	1.32
D	8.95	-	9.35
e	2.40	-	2.70
e1	4.95	-	5.15
E	10.00	-	10.40
L	13.00	-	14.00
L1	3.50	-	3.93
L2	1.27	-	1.40

Revision history

Table 9. Document revision history

Date	Revision	Changes
21-Jun-2023	1	First release. Part number previously included in datasheet DS5797.

Contents

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